JSCJ

ESD Report

Report NO.: MOS-E260196

1. Product Information

Supplier : JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO.,LTD.

Part Number:	CJU10N10
Package Type:	TO-252-2L
Report Date:	April-2026

2. Reference Standard

Item	Standards
1.Human-Body Model(HBM)	JESD22-A114
2.Machine Model(MM)	JESD22-A115

3. Classification Criteria

HBM Classification level	
Level	Test Voltage
CLASS 0	≤ 250V
CLASS 1A	> 250V to ≤ 500V
CLASS 1B	> 500V to ≤ 1000V
CLASS 1C	> 1000V to ≤ 2000V
CLASS 2	> 2000V to ≤ 4000V
CLASS 3A	> 4000V to ≤ 8000V
CLASS 3B	> 8000V

MM Classification level	
Level	Test Voltage
CLASS A	< 200V
CLASS B	≧ 200V to < 400V
CLASS C	≧ 400V

4. Test Result

Test Item	Test Condition	Samples	Class Level
HBM	Interval:1s 3Times /200V~8000V step:200V(±)	5PCS	CLASS 1B
MM	Interval:1s 3Times /200V~800V step:200V(±)	5PCS	CLASS B

Notes:

The failure criterion for the ESD test is based on whether the Device Under Test (DUT) meets its product specification (datasheet). Specifically, after being subjected to the specified ESD pulse stress, the device must undergo electrical parameter testing and functional checks. The device shall be considered failed if any of the following conditions occur:

1) Electrical parameters deviate from the limits specified in the datasheet;
2) Logic functions or preset functions cannot be realized.

Remark: JSCJ Laboratory reserves the right of final interpretation of this report